		Application/Control No.		Applicant(s)/Pat	Applicant(s)/Patent under Reexamination	
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		Examiner		Art Unit		
		Nguyen, Jennifer T		2629		
	ORIGINAL		INTE	RNATIONAL	INTERNATIONAL CLASSIFICATION	
CLASS		SUBCLASS	CLAIMED	ED	NON-CLAIMED	
345	86		S 6 0 S	2 / 00		
	CROSS REFERENCE(S)	CE(S)				
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Jennifer T. Nguyen (Assistant Examiner)	8/23/06 (Date)	RIU SUPERVISC TECHNO	RICHARD MJERPE SUPERVISORY PATENT EXAMINER TECHNOI OGY CENTER		Total Claims Allowed:	÷
Munder Klander) (Legal Instruments Examiner)	10/0/6 or) (Date)	(Primary Examiner)		To hale	O.G. O.G. Print Claim(s) Print	O.G. Print Figure 1

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